## nexperia

## **Reliability Monitoring Results**

## Quarters: Q1/2022 to Q4/2022

Based on structural similarity

| Suppli     | er   | User Part Number  |                             |           |            |              |
|------------|--|---|-----------------------------|-----------|------------|--------------|
| Nexperia   | a B.V.   |   |                             |           |            |              |
| Part D     | escription: Single inverter  | Schmitt-trigger   |                             |           |            |              |
| Pro<br>Pac | iction Family: HC(T)<br>cess family: Super micron<br>kage family: TSOP |   |                             |           |            | #            |
| JESD4      |  | Test Conditions   | Duration                    | # Lots    | # Quantity | Rejects      |
| # 1        | <b>TEST</b><br>Pre- and Post-Stress<br>Electrical Test                 | Tamb = 25 °C  | N/A                         | see below | all parts  | see<br>below |
| # 2        | <b>PC</b><br>Preconditioning   | JESD22-A113<br>MSL 1  | N/A                         | 156       | 12481      | 0            |
| # 5a       | HTOL EFR<br>High Temperature<br>Operating Life Extrinsic               | JESD22-A108<br>Tj = 150°C<br>$V_{CCMAX} \le V \le 1.2*V_{CCMAX}$  | 48 hours<br>or<br>168 hours | 63        | 23993      | 0            |
| # 5b       | HTOL IFR<br>High Temperature<br>Operating Life Intrinsic               | JESD22-A108<br>Tj = 150°C<br>$V_{CCMAX} \le V \le 1.2*V_{CCMAX}$  | ≥500 hours                  | 59        | 3272       | 0            |
| # 7        | TC<br>Temperature Cycling  | JESD22-A104<br>-65 °C to 150°C                                    | ≥500 cycles                 | 73        | 5846       | 0            |
| # 9        | uHAST / HAST<br>unbiased or biased High<br>Accelerated Stress Test     | JESD22-A101<br>Tamb = 130 °C,<br>RH = 85%, V = V <sub>CCMAX</sub> | 96 hours                    | 83        | 6635       | 0            |

## **Calculation of PPM, FIT and MTTF**

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above) Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic(HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Product<br>Family | Package<br>Family | Quantity | Rejects | Extrinsic<br>Failure Rate (PPM) | Intrinsic<br>Failure Rate (FIT) | MTTF (hrs) |
|-------------------|-------------------|----------|---------|---------------------------------|---------------------------------|------------|
| HC(T)             | TSOP              | 3272     | 0       | 39                              | 1.2                             | 8.84 E+08  |

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